

**INFORMATION DISCLOSURE CITATION**  
(Use several sheets if necessary)

Docket Number (Optional)

**BUR920010156US**

Application Number

**Unknown**

Applicant(s)

**Cooney et al.**

Filing Date

**Concurrently Herewith**

Group Art Unit

**Unknown**

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6,332,988	12/25/01	Berger, Jr. et al.			
		6,218,302	04/17/01	Braeckelmann et al.			
		5,480,812	01/02/96	Salisbury			

**FOREIGN PATENT DOCUMENTS**

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

		IEDM Technical Digest International; "COPPER DUAL DAMASCENE INTERCONNECTS WITH LOW-K DIELECTRICS"; Hasegawa et al; 1999IEEE; pp 623-626
		IEEE 2000 International; TUNGSTEN VIA POISONING CAUSED BY WATER TRAPPED IN EMBEDDED ORGANIC LOW-K DIELECTRICS"; Ikeda et al; 2000IEEE; pp158-160

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.